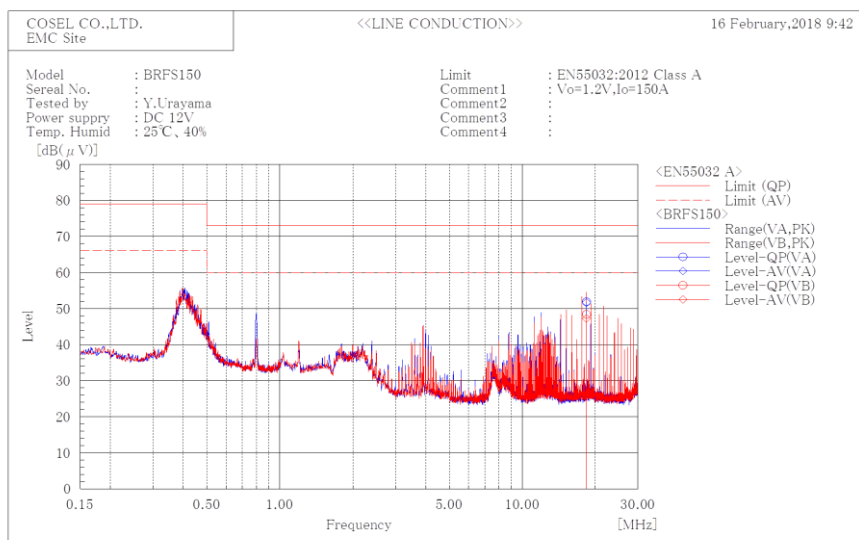
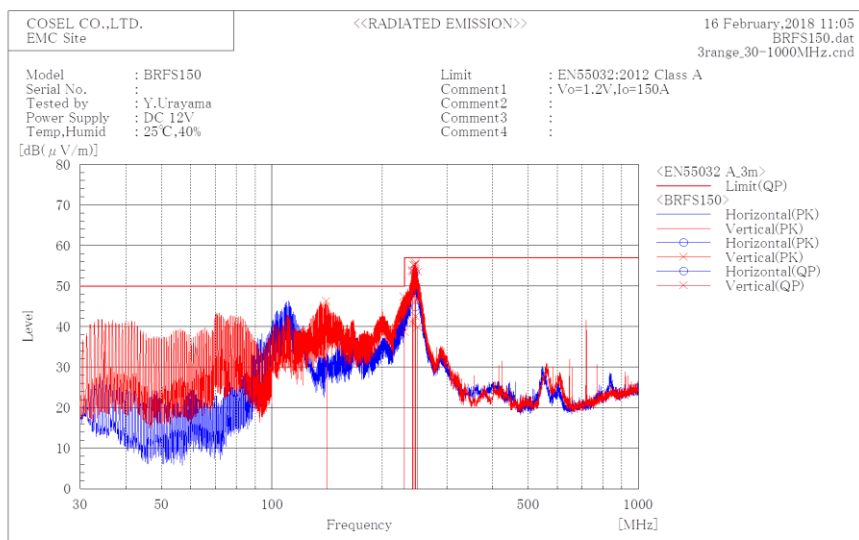


DATA SHEET		Date	16-Feb-18
Model	BRFS150	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	Y.Urayama



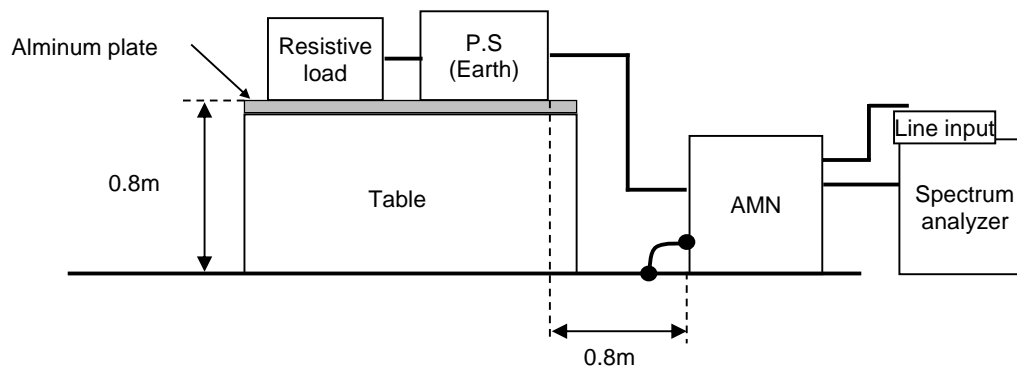
Frequency MHz	Line Phase	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
18.4053	VA	51.9	51.7	73	60	21.1	8.3	Pass	
18.3971	VB	48.4	47.3	73	60	24.6	12.7	Pass	



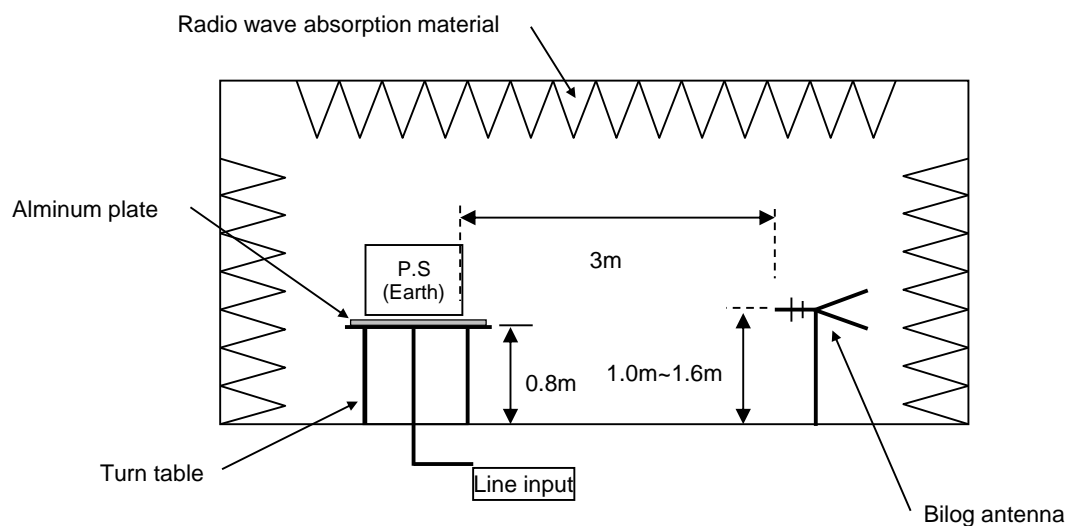
Frequency MHz	Polarization	Stability	Reading dB(μV)	Limit dB(μV/m)	Margin dB(μV/m)	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP	QP				
141.412	V	Stable	41.6	50.0	8.4	Pass	104	66	
245.465	V	Stable	49.1	57.0	7.9	Pass	157	102	
246.330	H	Stable	44.8	57.0	12.2	Pass	126	2	
246.535	V	Stable	46.5	57.0	10.5	Pass	148	97	

DATA SHEET		Date	16-Feb-18
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	Y.Urayama

## 1. Line conduction



## 2. Radiated emission



## Conditions

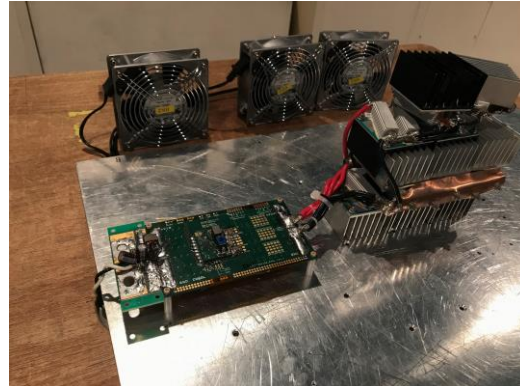
Test : EMI  
Model Name : BRFS150

○Photographs of Test Set-Up

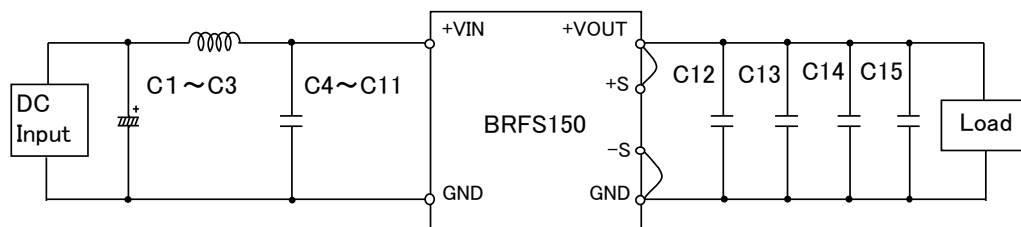
### LINE CONDUCTION



### RADIATED EMISSION



○Testing circuitry



C1~C3 : 25V 470  $\mu$  F Electric capacitor (KZHseries NIPPON CHEMI-CON)  
C4~C11 : 16V 22  $\mu$  F Ceramic capacitor (GRM32ER71C226K MURATRA MANUFACTURING)  
C12~C15 : 6.3V 100  $\mu$  F Ceramic capacitor (GRM32EE70J107M MURATRA MANUFACTURING)  
L1 : 0.3  $\mu$  H 36A Inductor (ETQP2H0R3BFA Panasonic Electronics Devices)